

L Number	Hits	Search Text	DB	Time stamp
1	2	6600171.pn. or 6680213.pn.	USPAT	2004/08/09 03:47
2	1972	257/750	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/09 03:50
3	2657	257/690	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/09 03:56
4	1973	257/691	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/09 04:08
5	2650	257/700	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/09 04:22
6	4668	257/758	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/09 05:30
7	2	5543364.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/09 05:25
8	923	257/759	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/09 05:43
9	1671	257/779	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/09 05:44
-	21743	(bad or defect\$3 or "non functional" or (none or "not" or non) near function\$2) with (semiconductor or die or chip or dice or IC)	USPAT	2004/08/08 20:31
-	21662	(bad or defect\$3 or "non functional") with (semiconductor or die or chip or dice or IC)	USPAT	2004/08/08 20:31
-	5340	(bad or defect\$3 or "non functional" or (none or "not" or non) near function\$2) near (semiconductor or die or chip or dice or IC)	USPAT	2004/08/08 20:32
-	5336	(bad or defect\$3 or "non functional" or (none or "not" or non) adj function\$2) near (semiconductor or die or chip or dice or IC)	USPAT	2004/08/08 20:32
-	2980	(bad or defect\$3 or "non functional" or (none or "not" or non) near function\$2) near (semiconductor or die or chip or dice or IC) and wafer	USPAT	2004/08/08 20:38
-	1326	((bad or defect\$3 or "non functional" or (none or "not" or non) near function\$2) near (semiconductor or die or chip or dice or IC) and wafer) and (repair\$3 or reconfigur\$3 or isolat\$3)	USPAT	2004/08/08 20:34
-	206	(bad or defect\$3 or "non functional" or (none or "not" or non) near function\$2) near (semiconductor or die or chip or dice or IC) with (repair\$3 or reconfigur\$3 or isolat\$3) and wafer	USPAT	2004/08/08 20:57

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-	179	(bad or defect\$3 or "non functional" or (none or "not" or non) near function\$2) near (semiconductor or die or chip or dice or IC) same (burn near in or "burn-in") near test\$3	USPAT	2004/08/09 01:34
-	17	((bad or defect\$3 or "non functional" or (none or "not" or non) near function\$2) near (semiconductor or die or chip or dice or IC) same (burn near in or "burn-in") near test\$3) and electric\$4 with isolat\$3	USPAT	2004/08/09 03:40